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| INFORMATION DISCLOSURE STATEMENT | | Atty. Docket No.: H16-25553 | | Serial No.: 09/345,335 | | |
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| | | Applicant(s): Guerlain et al. | | | | |
| | | Filing Date: July 1, 1999 | | Group: Unknown | | |
| U.S. PATENT DOCUMENTS | | | | | | |
| Examiner Initial | Document Number | Date | Name | Class | SubClass | Filing Date if Appropriate |
| ml | 5,347,466 | 09/13/94 | Iino et al. | | | |
| ml | 5,351,144 | 09/27/94 | Lu et al. | | | |
| ml | 5,408,406 | 04/18/95 | Mathur et al. | | | |
| ml | 5,572,420 | 11/05/96 | Lu | | | |
| ml | 5,768,119 | 06/16/98 | Havekost et al. | | | |
| ml | 5,838,588 | 11/17/98 | Santoso et al. | | | |
| FOREIGN PATENT DOCUMENTS | | | | | | |
| | Document Number | Date | Country | Class | SubClass | Translation |
| | NONE | | | | | Yes No |
| | | | | | | |
| | | | | | | |
| OTHER DOCUMENTS (Including Authors, Title, Date, Pertinent Papers, etc.) | | | | | | |
| ml | | | Bakshi et al., "Representation of Process Trends-III. Multiscale Extraction of Trends from Process Data," <u>Computers & Chemical Engineering</u> , 18(4), pp. 267-302 (1994). | | | |
| ml | | | Beuthel et al., "Advantages of Mass-Data-Displays in Process S&C," <u>Analysis, Design and Evaluation of Man-Machine Systems 1995</u> , (A Postprint volume from the IFAC Symposium Cambridge, Massachusetts), 2, pp. 383-388 (1995). | | | |
| ml | | | Cheung et al., "Representation of Process Trends. Part I. A Formal Representation Framework," <u>Computers & Chemical Engineering</u> , 14(4/5), pp.495-510 (1990). | | | |
| ml | | | Janusz et al., "Automatic Generation of Qualitative Descriptions of Process Trends for Fault Detection and Diagnosis," <u>Engng. Applic. Artif. Intell.</u> , 4(5), pp. 329-339 (1991). | | | |
| ml | | | Lambert et al., "Design Of a New Human-Machine System For the Supervision Of a Highly Automated Continuous Process," SMC'98, San Diego, 6 pgs.(1998). | | | |

EXAMINER

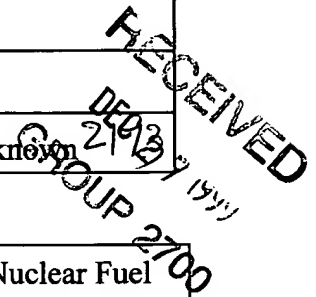
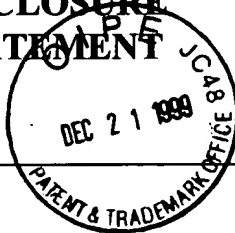
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Date Considered

10/18/01

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| | Applicant(s): Guerlain et al. | |
| | Filing Date: July 1, 1999 | Group: Unknown |



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| ml | | Lambert et al., "Design of a New Interface for The Supervision of a Nuclear Fuel Reprocessing System," <u>Time And Space In Process Control</u> , CSAPC'97, pp. 195-199 (1997). |
| ml | | Lambert et al., "Design of a New Supervision System Involving New Man-Machine Interactions," <u>Computational Engineering in Systems Applications</u> IMACS Multiconference, Nabeul-Hammamet, Tunisia, 7 pgs.(April 1-4, 1998). |
| ml | | Lambert et al., "Realization and Evaluation of a New Kind of Supervisory System," <u>Preprints of the 7th IFAC/IFIP/IFORS/IEA Symposium on Analysis, Design and Evaluation of Man-Machine Systems</u> , Koyto, Japan, pp. 455-460 (September 16-18, 1998). |
| ml | | Rengaswamy et al., "A Syntactic Pattern-Recognition Approach for Process Monitoring and Fault Diagnosis," <u>Engng. Applic. Artif. Intell.</u> , 8(1), pp. 35-51 (1995). |
| ml | | "Robust Multivariable Predictive Control Technology-RMPCT Users Guide for TPS," Honeywell product publication, pp. 1-147 (June 1997). |
| ml | | Xia, "Similarity Search in Time Series Data Sets," M.S. Thesis, Simon Fraser University, pp. 1-97 (1997). |
| EXAMINER  | | Date Considered 10/17/01 |

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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| Form PTO-1449 LIST FOR INFORMATION DISCLOSURE STATEMENT <i>(Use several sheets if necessary)</i> | | Atty. Docket No. H16-25553 US | | Serial No. 09/345,335 | |
| | | Applicant GUERLAIN, ET AL | | | |
| | | Filing Date 07/01/99 | | Group 2776 2173 | |

| *EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS** | SUBCLASS** | FILING DATE IF APPROPRIATE |
|----------------------|-----------------|----------|-------------|---------|------------|-------------------------------|
| ml | 5 7 4 2 5 0 0 | 4/21/98 | IRVIN | | | |
| ml | 5 7 4 8 4 9 5 | 05/05/98 | ARITA ET AL | | | |
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| FOREIGN PATENT DOCUMENTS | | | | | | | | | |
|--------------------------|----------|---------|-------|----------|-----------------------|--|--|--|--|
| DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION YES NO | | | | |
| ml 0 4 3 2 1 3 8 A | 6/12/91 | EP | | | | | | | |
| ml 9 1 1 0 3 4 8 U | 11/21/91 | DE | | | | | | | |
| ml 9 7 2 2 0 7 2 A | 6/19/97 | WO | | | | | | | |
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| OTHER DOCUMENTS <small>(Including Author, Title, Date, Pertinent Pages, Etc.)</small> | |
|---|--|
| ml | MAIER U: "DAS PROZESSLEITSYSTEM CENTUM CS VON YOKOGAWA" AUTOMATISIERUNGSTECHNISCHE PRAXIS – ATP, DE, OLDENBOURG VERLAG. MUNCHEN. VOL.36, NO. 5, 1 MAY 1994 (1994-05-01), PAGES 48-50, 52-54., XP000446989, ISSN: 0178-2320 THE WHOLE DOCUMENT |
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